

GENERAL

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Small-signal and Medium-power MOS transistors

General

QUALITY

Total Quality Management

Philips Semiconductors is a Quality Company, renowned for the high quality of our products and service. We keep alive this tradition by constantly aiming towards one ultimate standard, that of zero defects. This aim is guided by our Total Quality Management (TQM) system which is described in our Quality manuals. The basis is outlined in the following paragraphs.

QUALITY ASSURANCE

Based on ISO 9000 standards, customer standards such as FDC, QS9000 and IBM MDQ. Our factories are certified to ISO 9000 by external inspectorates.

PARTNERSHIPS WITH CUSTOMERS

PPM co-operations, design-in agreements, ship-to-stock, just-in-time, self-qualification programmes, and application support.

PARTNERSHIPS WITH SUPPLIERS

Ship-to-stock, statistical process control and ISO 9000 audits.

QUALITY IMPROVEMENT PROGRAMME

Continuous process and system improvement, design improvement, complete use of statistical process control, realization of our final objective of zero defects, and logistics improvement by ship-to-stock and just-in-time agreements.

Advanced quality planning

During the design and development of new products and processes, quality is built-in by advanced quality planning. Through failure-mode-and-effect analysis the critical parameters are detected and measures taken to ensure good performance on these parameters. The capability of process steps is also planned in this phase in preparation for production under statistical process control.

Product conformance

The assurance of product conformance is an integral part of our quality assurance (QA) practice. This is achieved by:

- Incoming material management through partnerships with suppliers
- In-line quality assurance to monitor process reproducibility during manufacture and initiate any

necessary corrective action. Process steps are under statistical process control

- Acceptance tests on finished products to verify conformance with the device specification. The test results are used for quality feedback and corrective actions. The inspection and test requirements are detailed in the general quality specifications SNW-EQ-611 part A
- Periodic inspections to monitor and measure the conformance of products
- Qualification tests (see SNW-EQ-611 part A).

Product reliability

With the increasing complexity of Original Equipment Manufacturer (OEM) equipment, component reliability must be extremely high. Our research laboratories and development departments study the failure mechanisms of semiconductors. Their studies result in design rules and process optimization for the highest built-in product reliability. Highly accelerated tests are applied to the product's reliability evaluation. Rejects from reliability tests and from customer complaints are submitted to failure analysis, to result in corrective action.

Customer response

Our quality improvement depends on joint action with our customer. We need our customer's inputs and we invite constructive comments on all aspects of our performance. Please contact our local sales representative.

Recognition

The high quality of our products and services is demonstrated by many Quality Awards granted by major customers and international organizations.

PRO ELECTRON TYPE NUMBERING SYSTEM

Basic type number

This type designation code applies to discrete semiconductor devices (not integrated circuits), multiples of such devices, semiconductor chips and Darlington transistors.

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FIRST LETTER

The first letter gives information about the material for the active part of the device.

- A Germanium or other material with a band gap of 0.6 to 1 eV
- B Silicon or other material with a band gap of 1 to 1.3 eV
- C Gallium arsenide (GaAs) or other material with a band gap of 1.3 eV or more
- R Compound materials, e.g. cadmium sulphide.

SECOND LETTER

The second letter indicates the function for which the device is primarily designed. The same letter can be used for multi-chip devices with similar elements.

In the following list low power types are defined by $R_{th\ j-mb} > 15\ K/W$ and power types by $R_{th\ j-mb} \leq 15\ K/W$.

- A Diode; signal, low power
- B Diode; variable capacitance
- C Transistor; low power, audio frequency
- D Transistor; power, audio frequency
- E Diode; tunnel
- F Transistor; low power, high frequency
- G Multiple of dissimilar devices/miscellaneous devices; e.g. oscillators. Also with special third letter; see under Section "Serial number".
- H Diode; magnetic sensitive
- L Transistor; power, high frequency
- N Photocoupler
- P Radiation detector; e.g. high sensitivity photo-transistor; with special third letter
- Q Radiation generator; e.g. LED, laser; with special third letter
- R Control or switching device; e.g. thyristor, low power; with special third letter
- S Transistor; low power, switching
- T Control or switching device; e.g. thyristor, power; with special third letter
- U Transistor; power, switching
- W Surface acoustic wave device
- X Diode; multiplier, e.g. varactor, step recovery
- Y Diode; rectifying, booster
- Z Diode; voltage reference or regulator, transient suppressor diode; with special third letter.

SERIAL NUMBER

The number comprises three figures running from 100 to 999 for devices primarily intended for consumer equipment, or one letter (Z, Y, X, etc.) and two figures running from 10 to 99 for devices primarily intended for industrial or professional equipment.⁽¹⁾

Version letter

A letter may be added to the basic type number to indicate minor electrical or mechanical variants of the basic type.

RATING SYSTEMS

The rating systems described are those recommended by the IEC in its publication number 134.

Definitions of terms used

ELECTRONIC DEVICE

An electronic tube or valve, transistor or other semiconductor device. This definition excludes inductors, capacitors, resistors and similar components.

CHARACTERISTIC

A characteristic is an inherent and measurable property of a device. Such a property may be electrical, mechanical, thermal, hydraulic, electro-magnetic or nuclear, and can be expressed as a value for stated or recognized conditions. A characteristic may also be a set of related values, usually shown in graphical form.

BOGEY ELECTRONIC DEVICE

An electronic device whose characteristics have the published nominal values for the type. A bogey electronic device for any particular application can be obtained by considering only those characteristics that are directly related to the application.

RATING

A value that establishes either a limiting capability or a limiting condition for an electronic device. It is determined for specified values of environment and operation, and may be stated in any suitable terms. Limiting conditions may be either maxima or minima.

(1) When the supply of these serial numbers is exhausted, the serial number may be expanded to three figures for industrial types and four figures for consumer types.

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RATING SYSTEM

The set of principles upon which ratings are established and which determine their interpretation. The rating system indicates the division of responsibility between the device manufacturer and the circuit designer, with the object of ensuring that the working conditions do not exceed the ratings.

Absolute maximum rating system

Absolute maximum ratings are limiting values of operating and environmental conditions applicable to any electronic device of a specified type, as defined by its published data, which should not be exceeded under the worst probable conditions.

These values are chosen by the device manufacturer to provide acceptable serviceability of the device, taking no responsibility for equipment variations, environmental variations, and the effects of changes in operating conditions due to variations in the characteristics of the device under consideration and of all other electronic devices in the equipment.

The equipment manufacturer should design so that, initially and throughout the life of the device, no absolute maximum value for the intended service is exceeded with any device, under the worst probable operating conditions with respect to supply voltage variation, equipment component variation, equipment control adjustment, load variations, signal variation, environmental conditions, and variations in characteristics of the device under consideration and of all other electronic devices in the equipment.

Design maximum rating system

Design maximum ratings are limiting values of operating and environmental conditions applicable to a bogey electronic device of a specified type as defined by its published data, and should not be exceeded under the worst probable conditions.

These values are chosen by the device manufacturer to provide acceptable serviceability of the device, taking responsibility for the effects of changes in operating conditions due to variations in the characteristics of the electronic device under consideration.

The equipment manufacturer should design so that, initially and throughout the life of the device, no design maximum value for the intended service is exceeded with a bogey electronic device, under the worst probable operating conditions with respect to supply voltage variation, equipment component variation, variation in

characteristics of all other devices in the equipment, equipment control adjustment, load variation, signal variation and environmental conditions.

Design centre rating system

Design centre ratings are limiting values of operating and environmental conditions applicable to a bogey electronic device of a specified type as defined by its published data, and should not be exceeded under normal conditions.

These values are chosen by the device manufacturer to provide acceptable serviceability of the device in average applications, taking responsibility for normal changes in operating conditions due to rated supply voltage variation, equipment component variation, equipment control adjustment, load variation, signal variation, environmental conditions, and variations in the characteristics of all electronic devices.

The equipment manufacturer should design so that, initially, no design centre value for the intended service is exceeded with a bogey electronic device in equipment operating at the stated normal supply voltage.

LETTER SYMBOLS

The letter symbols for transistors detailed in this section are based on IEC publication number 148.

Letter symbols for currents, voltages and powers

BASIC LETTERS

I, i current

V, v voltage

P, p power.

Upper-case letter symbols are used to represent all values except instantaneous values that vary with time, these are represented by lower-case letters.

SUBSCRIPTS

A, a anode terminal

(AV), (av) average value

B, b base terminal

(BO) breakover

(BR) breakdown

C, c collector terminal

D, d drain terminal

E, e emitter terminal

F, f forward

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G, g	gate terminal
H	holding
I, i	input
K, k	cathode terminal
L	load
M, m	peak value
(min)	minimum
(max)	maximum
O, o	as third subscript: the terminal not mentioned is open-circuit
(OV)	overload
P, p	pulse
R, r	as first subscript: reverse. As second subscript: repetitive. As third subscript: with a specified resistance between the terminal not mentioned and the reference terminal
(RMS), (rms)	root-mean-square value
S, s	as first or second subscript: source terminal (FETs only). As second subscript: non-repetitive (not FETs). As third subscript: short circuit between the terminal not mentioned and the reference terminal
TO	threshold
tot	total
W	working
X, x	specified circuit
Z, z	replaces R to indicate the actual working voltage, current or power of voltage reference and voltage reference diodes.

No additional subscript is used for DC values.

Upper-case subscripts are used for the indication of:

- Continuous (DC) values (without signal), e.g. I_D
- Instantaneous total values, e.g. i_D
- Average total values, e.g. $I_{D(AV)}$
- Peak total values, e.g. I_{DM}
- Root-mean-square total values, e.g. $I_{D(RMS)}$.

Lower-case subscripts are used for the indication of values applying to the varying component alone:

- Instantaneous values, e.g. i_d
- Root-mean-square values, e.g. $i_{d(rms)}$
- Peak values, e.g. I_{dm}
- Average values, e.g. $I_{d(av)}$.

If more than one subscript is used, the subscript for which both styles exist are either all upper-case or all lower-case.

ADDITIONAL RULES FOR SUBSCRIPTS

Transistor currents

If it is necessary to indicate the terminal carrying the current, this should be done by the first subscript (conventional current flow from the external circuit into the terminal is positive).

Examples: I_D , i_D , i_d , I_{dm} .

Transistor voltages

If it is necessary to indicate the points between which a voltage is measured, this should be done by the first two subscripts. The first subscript indicates the terminal at which the voltage is measured and the second the reference terminal or the circuit node. Where there is no possibility of confusion, the second subscript may be omitted.

Examples: V_{GS} , v_{GS} , V_{gs} , V_{gsm} .

Supply voltages or currents

Supply voltages or supply currents are indicated by repeating the appropriate terminal subscript.

Examples: V_{DD} , I_{SS} .

If it is necessary to indicate a reference terminal, this should be done by a third subscript.

Example: V_{DDS} .

Subscripts for devices with more than one terminal of the same kind

If a device has more than one terminal of the same kind, the subscript is formed by the appropriate letter for the terminal, followed by a number. In the case of multiple subscripts, hyphens may be necessary to avoid confusion.

Examples:

I_{G2} continuous (DC) current flowing into the second gate terminal

V_{G2-S} continuous (DC) voltage between the second gate and source terminals.

Subscripts for multiple devices

For multiple unit devices, the subscripts are modified by a number preceding the letter subscript. In the case of multiple subscripts, hyphens may be necessary to avoid confusion.

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Examples:

I_{2D} continuous (DC) current flowing into the drain terminal of the second unit

V_{1D-2D} continuous (DC) voltage between the drain terminals of the first and second units.

Letter symbols for electrical parameters

DEFINITION

For the purpose of this publication, the term 'electrical parameter' applies to four-pole matrix parameters, elements of electrical equivalent circuits, electrical impedances and admittances, inductances and capacitances.

BASIC LETTERS

The following list comprises the most important basic letters used for electrical parameters of semiconductor devices.

B, b	susceptance (imaginary part of an admittance)
C	capacitance
G, g	conductance (real part of an admittance)
H, h	hybrid parameter
L	inductance
R, r	resistance (real part of an impedance)
X, x	reactance (imaginary part of an impedance)
Y, y	admittance
Z, z	impedance.

Upper-case letters are used for the representation of:

- Electrical parameters of external circuits and of circuits in which the device forms only a part
- All inductances and capacitances.

Lower-case letters are used for the representation of electrical parameters inherent in the device, with the exception of inductances and capacitances.

SUBSCRIPTS

General subscripts

The following list comprises the most important general subscripts used for electrical parameters of semiconductor devices.

F, f	forward (forward transfer)
I, i (or 1)	input
L, l	load
O, o (or 2)	output

R, r reverse (reverse transfer)

S, s source.

Examples: Z_s , g_f , g_F .

The upper-case variant of a subscript is used for the designation of static (DC) values.

Examples:

g_{FS} static value of forward transconductance in common-source configuration (DC current gain)

R_{DS} DC value of the drain-source resistance.

The static value is the slope of the line from the origin to the operating point on the appropriate characteristic curve, i.e. the quotient of the appropriate electrical quantities at the operating point.

The lower-case variant of a subscript is used for the designation of small-signal values.

Examples:

g_{fs} small-signal value of the short-circuit forward transconductance in common-source configuration

$Z_i = R_i + jX_i$ small-signal value of the input impedance.

If more than one subscript is used, subscripts for which both styles exist are either all upper-case or all lower-case.

Examples: g_{FS} , g_{fs} .

THERMAL CONSIDERATIONS

Thermal resistance

Circuit performance and long-term reliability are affected by the temperature of the transistor die. Normally, both are improved by keeping the die temperature (junction temperature) low.

Electrical power dissipated in any semiconductor device is a source of heat. This increases the temperature of the die about some reference point, normally an ambient temperature of 25 °C in still air. The size of the increase in temperature depends on the amount of power dissipated in the circuit and the net thermal resistance between the heat source and the reference point.

Devices lose most of their heat by conduction when mounted on a printed board, a substrate or heatsink. Referring to Fig.1 (for surface mounted devices mounted on a substrate), heat conducts from its source (the junction) via the package leads and soldered connections to the substrate. Some heat radiates from the package into the surrounding air where it is dispersed by convection or

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by forced cooling air. Heat that radiates from the substrate is dispersed in the same way.

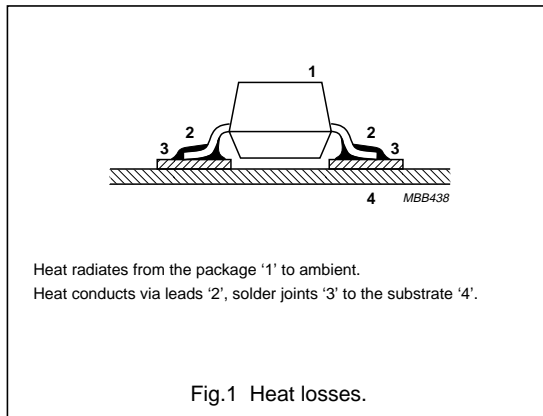


Fig.1 Heat losses.

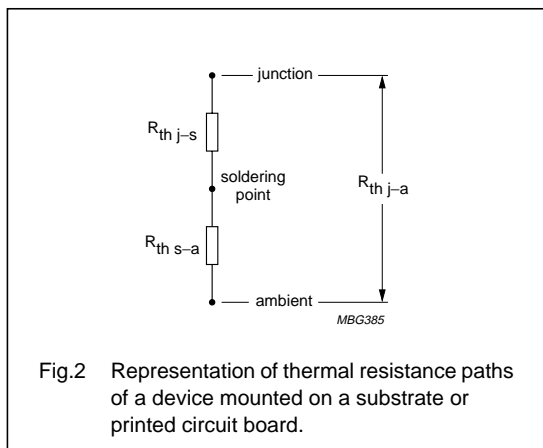


Fig.2 Representation of thermal resistance paths of a device mounted on a substrate or printed circuit board.

The elements of thermal resistance shown in Fig.2 are defined as follows:

- $R_{th\ j-mb}$ thermal resistance from junction to mounting base
- $R_{th\ j-c}$ thermal resistance from junction to case
- $R_{th\ j-s}$ thermal resistance from junction to soldering point
- $R_{th\ s-a}$ thermal resistance from soldering point to ambient
- $R_{th\ c-a}$ thermal resistance from case to ambient ($R_{th\ s-a}$ and $R_{th\ c-a}$ are the same for most packages)
- $R_{th\ j-a}$ thermal resistance from junction to ambient.

The temperature at the junction depends on the ability of the package and its mounting to transfer heat from the junction region to the ambient environment. The basic relationship between junction temperature and power dissipation is:

$$T_{j\ max} = T_{amb} + P_{tot\ max} (R_{th\ j-s} + R_{th\ s-a})$$

$$= T_{amb} + P_{tot\ max} (R_{th\ j-a})$$

where:

- $T_{j\ max}$ is the maximum junction temperature
- T_{amb} is the ambient temperature
- $P_{tot\ max}$ is the maximum power handling capability of the device, including the effects of external loads when applicable.

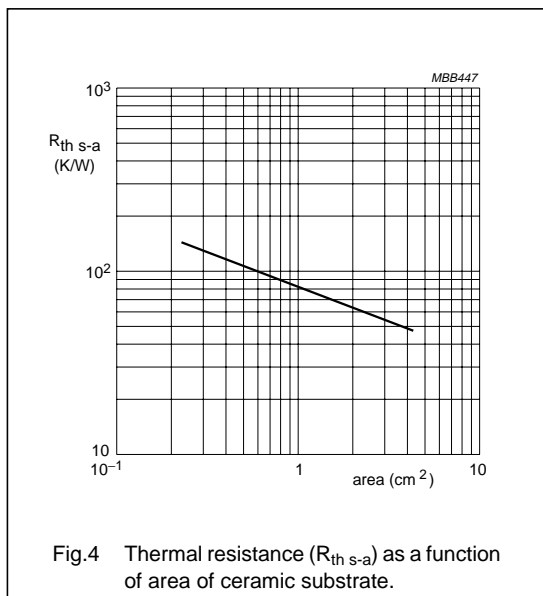
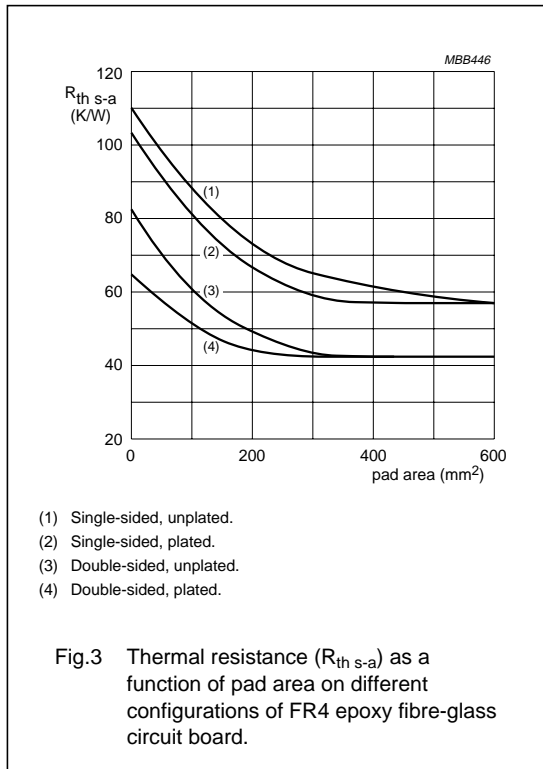
In the expression for $T_{j\ max}$, only T_{amb} and $R_{th\ s-a}$ can be varied by the user. The package mounting technique and the flow of cooling air are factors that affect $R_{th\ s-a}$. The device power dissipation can be controlled to a limited extent but under recommended usage, the supply voltage and circuit loading dictate a fixed power maximum. The $R_{th\ j-s}$ value is essentially independent of external mounting method and cooling air; but is sensitive to the materials used in the package construction, the die bonding method and the die area, all of which are fixed.

Values of $T_{j\ max}$ and $R_{th\ j-s}$, or $R_{th\ j-c}$ or $R_{th\ j-a}$ are given in the device data sheets. For applications where the temperature of the case is stabilized by a large or temperature-controlled heatsink, the junction temperature can be calculated from:

$$T_j = T_{case} + P_{tot} \times R_{th\ j-c} \text{ or, using the soldering point } (T_s) \text{ definition, from } T_j = T_s + P_{tot} \times R_{th\ j-s}.$$

The thermal resistance from soldering point to ambient, and that from case to ambient depends on the substrate or PCB material used.

Refer to figures 3 and 4 for R_{th} versus mounting substrate area.



HANDLING MOS DEVICES

Electrostatic charges

Electrostatic charges can exist in many things; for example, man-made-fibre clothing, moving machinery, objects with air blowing across them, plastic storage bins, sheets of paper stored in plastic envelopes, paper from electrostatic copying machines, and people. The charges are caused by friction between two surfaces, at least one of which is non-conductive. The magnitude and polarity of the charges depend on the different affinities for electrons of the two materials rubbing together, the friction force and the humidity of the surrounding air.

Electrostatic discharge is the transfer of an electrostatic charge between bodies at different potentials and occurs with direct contact or when induced by an electrostatic field. Our MOS devices **can** be damaged if the following precautions are not taken.

Work station

Figure 5 shows a working area suitable for safely handling electrostatic sensitive devices. It has a work bench, the surface of which is conductive or covered by an antistatic sheet. Typical resistivity for the bench surface is between 1 and 500 $k\Omega$ per cm^2 . The floor should also be covered with antistatic material.

The following precautions should be observed:

- Persons at a work bench should be earthed via a wrist strap and a resistor
- All mains-powered electrical equipment should be connected via an earth leakage switch
- Equipment cases should be earthed
- Relative humidity should be maintained between 50 and 65%
- An ionizer should be used to neutralize objects with immobile static charges.

Receipt and storage

MOS devices are packed for dispatch in antistatic conductive containers, usually boxes, tubes or blister tape. The fact that the contents are sensitive to electrostatic discharge is shown by warning labels on both primary and secondary packing.

The devices should be kept in their original packing whilst in storage. If a bulk container is partially unpacked, the unpacking should be performed at a protected work station. Any MOS devices that are stored temporarily

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should be packed in conductive or antistatic packing or carriers.

Assembly

MOS devices must be removed from their protective packing with earthed component pincers or short-circuit clips. Short-circuit clips must remain in place during mounting, soldering and cleansing/drying processes. Do not remove more devices from the storage packing than are needed at any one time. Production/assembly documents should state that the product contains electrostatic sensitive devices and that special precautions need to be taken.

During assembly, ensure that the MOS devices are the last of the components to be mounted and that this is done at a protected work station.

All tools used during assembly, including soldering tools and solder baths, must be earthed. All hand tools should be of conductive or antistatic material and, where possible, should not be insulated.

Measuring and testing of completed circuit boards must be done at a protected work station. Place the soldered side of the circuit board on conductive or antistatic foam and remove the short-circuit clips. Remove the circuit board from the foam, holding the board only at the edges. Make sure the circuit board does not touch the conductive surface of the work bench. After testing, replace the circuit board on the conductive foam to await packing.

Assembled circuit boards containing MOS devices should be handled in the same way as unmounted MOS devices. They should also carry warning labels and be packed in conductive or antistatic packing.

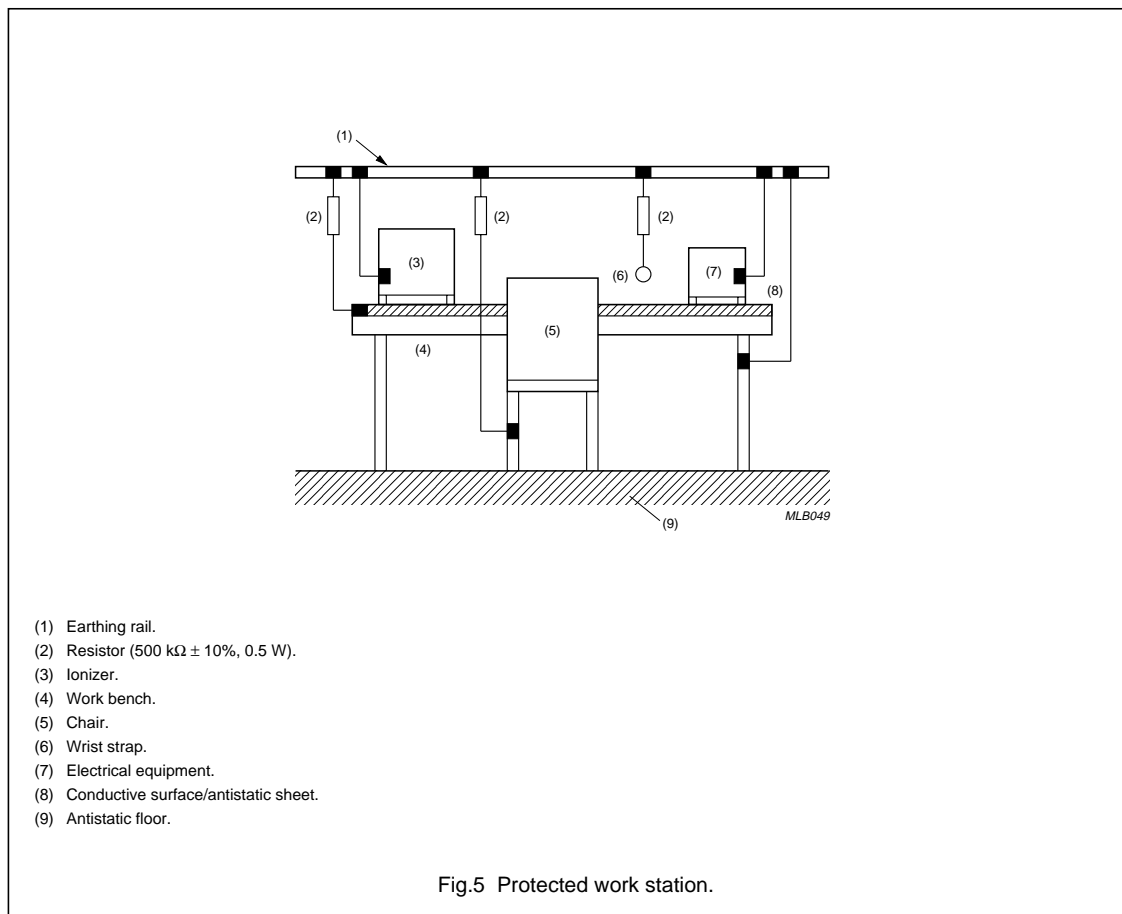


Fig.5 Protected work station.

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